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### Tau ID efficiency measurement

S3Be workshop January the 24<sup>th</sup>, 2014 Cécile Caillol

### Objectives

- Measurement of tau ID efficiency data/MC scale factor:
  - Is it equal to 1.0?
  - What is its uncertainty?
  - Does the scale factor depend on tau pT?
  - Does the efficiency depend on the event topology (Drell Yan, ttbar)?

#### **ULB Method** $- Z \rightarrow \tau_h \tau_\mu$ events **ULB Selection in brief:** - 1 isolated muon - 1 OS loose tau - MT ( $\mu$ ,MET)<40 GeV - $P_{\xi} = P_{\xi}^{mis} - 0.85P_{\xi}^{vis} > -15$ GeV

- Divide events whether the tau passes/fails ID (decay mode finding + isolation)
- Fit simultaneously both regions with:
  - Parameter of interest (POI) : tau ID efficiency scale factor
  - Nuisance parameters: luminosity, cross-sections, tau fake rate, MET uncertainties, ...
- Tau ID parameter is anti-correlated between "Pass" and "Fail" regions!

### **Background estimation**

- Signal: From MC DYJets,  $Z \rightarrow \tau_h \tau_\mu$  where the real tau and the real muon have been selected.
- **DY others**: All the other DY events, mainly  $Z \rightarrow \mu\mu$ ,  $Z \rightarrow \tau_{\mu}\tau_{\mu}$  and  $Z \rightarrow \tau_{h}\tau_{\mu}$  where the wrong leptons have been selected; from MC.
- **ttbar**: from MC.
- W+jets: Shape from MC, normalization from high M<sub>T</sub> (M<sub>T</sub>>70 GeV) sideband.
- QCD: shape and normalization from SS region.

#### Uncertainties



	Signal	DY others	W+jets	QCD	TTbar
Luminosity	2.6%	2.6%	-	-	2.6%
DY xs	3.0%	3.0%	-	-	-
ttbar xs	-	-	-	-	15%
W+jets norm	-	-	3%	-	-
Mu ID/iso	2.0%	2.0%	-	-	2.0%
QCD norm (shape)	-	-	-	yes	-
QCD OS/SS extrap.	-	-	-	5%	-
Tau scale (shape)	3.0%	3.0%	3.0%	3.0%	3.0%
Tau FR (shape)	-	30.0%	-	-	30.0%
bin-by-bin (threshold=0.05)	yes	yes	yes	yes	yes
Tracking (shape)	3.8%	3.8%	3.8%	-	3.8%
Hadronization (shape)	-	10.0%	10.0%	-	10.0%

Fully correlated

Uncorrelated Anti-correlated

between pass and fail

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# "Pass" fit - $Z \rightarrow \tau_h \tau_\mu$ events



Observable: m<sub>visible</sub> (μ,τ)

# "Fail" fit - $Z \rightarrow \tau_h \tau_\mu$ events



Scale factor: 0.950 +/- 0.046 ("Pass" and "Fail" fitted simultaneously)

### Fit – $Z \rightarrow \tau_h \tau_\mu$ events



- N<sub>tracks</sub>: number of charged tracks in tau isolation and signal cones
  Variable independent of tau pT!
- Data/MC scale factor (HPS loose 3 Hits): 0.96 +/- 0.04
  - $\rightarrow$  Compatible with measurement using m<sub>vis</sub> as observable

## First measurement in tau pT bins



### Method – tt $\rightarrow \mu \tau_h$ events

- Selection overview:
  - IsoMu24 trigger
  - 1 isolated muon
  - 1 OS loose tau
  - 2 or 3 jets with pT>30 GeV
  - At least 1 b-jet
  - MET > 40 GeV
- "Fail" region idle because of too small signal fraction → Use a ttbar control region instead to control nuisance parameters
- Selection in ttbar control region similar as signal region but:
  - 2 isolated OS muons
  - 1 loose tau failing ID

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### Results – tt $\rightarrow \mu \tau_h$ events



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Discriminator	MC efficiency	Scale factor
Combined isolation 8-hit Loose <sup>1</sup>	59.1%	$1.001\pm0.098$
Combined isolation 8-hit Medium <sup>1</sup>	47.5%	$0.964\pm0.107$
Combined isolation 8-hit Tight <sup>1</sup>	43.8%	$0.977\pm0.114$
Combined isolation 3-hit Loose <sup>1</sup>	58.4%	$0.976\pm0.097$
Combined isolation 3-hit Medium <sup>1</sup>	46.4%	$0.970\pm0.102$
Combined isolation 3-hit Tight <sup>1</sup>	42.8%	$0.994\pm0.112$
MVA isolation Loose <sup>1</sup>	65.2%	$1.138\pm0.100$
MVA isolation Medium <sup>1</sup>	55.6%	$1.053\pm0.101$
MVA isolation Tight <sup>1</sup>	46.8%	$1.004\pm0.105$
MVA2 isolation Loose <sup>1</sup>	65.9%	$1.089 \pm 0.098$
MVA2 isolation Medium <sup>1</sup>	60.2%	$1.064\pm0.105$
MVA2 isolation Tight <sup>1</sup>	52.2%	$1.060\pm0.108$

### Summary

- Tau ID efficiency measured in data in DY and ttbar events
- Scale factors more or less compatible with 1.0 (slight trend to be lower)
- Efficiency smaller in ttbar events than in Drell-Yan events due to higher hadronic activity
- Complementary to  $Z \rightarrow \mu \mu / Z \rightarrow \tau \tau$  ratio method, but possibility to measure efficiency in bins of tau pT
- Scale factors independent of tau pT
- Next step is to measure scale factors for new tau ID discriminators
- Results to be published in a tau performance paper (summer 2014).



#### **BACK-UP**

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### Control distribution (P zeta)



Pass

Fail

